

PART NUMBER 5420BDA-ROCS

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All re-creations are done with the approval of the Original Component Manufacturer. (OCM)

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level

Qualified Suppliers List of Distributors (QSLD)

 Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OCM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.



M38510-001 (5401)

Microcircuits, Digital, TTL, NAND Gates, Monolithic Silicon

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INCH-POUND
MIL-M-38510/1F
16 March 2005
SUPERSEDING
MIL-M-38510/1E
1 June 1982

MILITARY SPECIFICATION

MICROCIRCUITS, DIGITAL, TTL, NAND GATES, MONOLITHIC SILICON

This specification is approved for use by all Departments and Agencies of the Department of Defense.

The requirements for acquiring the product herein shall consist of this specification sheet and MIL-PRF 38535

- 1. SCOPE
- 1.1 <u>Scope.</u> This specification covers the detail requirements for monolithic silicon, TTL, positive NAND logic gating microcircuits. Two product assurance classes and a choice of case outlines and lead finishes are provided for each type and are reflected in the complete part number. For this product, the requirements of MIL-M-38510 have been superseded by MIL-PRF-38535, (see 6.3).
 - 1.2 Part or Identifying Number (PIN). The PIN is in accordance with MIL-PRF-38535, and as specified herein.
 - 1.2.1 Device types. The device types are as follows:

Device type	<u>Circuit</u>
01	Single, 8-input positive NAND gate
02	Dual, 4-input positive NAND gate
03	Triple, 3-input positive NAND gate
04	Quadruple, 2-input positive NAND gate
05	Hex, 1-input inverter gate
06	Triple, 3-input positive NAND gate (open collector output)
07	Quadruple, 2-input positive NAND gate (open collector output)
08	Hex, 1-input inverter gate (open collector output)
09	Same as device type 07, except different pin connections

- 1.2.2 Device class. The device class is the product assurance level as defined in MIL-PRF-38535.
- 1.2.3 <u>Case outlines.</u> The case outlines are as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	<u>Terminals</u>	Package style
Α	GDFP5-F14 or CDFP6-F14	14	Flat
В	GDFP4-F14	14	Flat
С	GDIP1-T14 or CDIP2-T14	14	Dual-in-line
D	GDFP1-F14 or CDFP2-F14	14	Flat

Comments, suggestions, or questions on this document should be addressed to: Commander, Defense Supply Center Columbus, ATTN: DSCC-VAS, P.O. Box 3990, Columbus, OH 43218-3990, or emailed to bipolar@dla.mil. Since contact information can change, you may want to verify the currency of this address information using the ASSIST Online database at http://assist.daps.dla.mil.

AMSC N/A FSC 5962

1.3 Absolute maximum ratings.

	Supply voltage range	-0.5 V to +7.0 V
	Input voltage range	-1.5 V at -12 mA to +5.5 V
	Storage temperature range	-65° to +150°C
	Maximum power dissipation per gate (P _D) 1/	. 40 mW
	Lead temperature (soldering, 10 seconds)	300°C
	Thermal resistance, junction to case (θ_{JC})	(See MIL-STD-1835)
	Junction temperature (T _J) 2/	175°C
1	Recommended operating conditions.	
	Supply voltage	+4.5 V minimum to +5.5 V maximum

1.4

Supply voltage	+4.5 V minimum to +5.5 V maximum
Minimum high level input voltage	+2.0 V
Maximum low level input voltage (V _{IL})	+0.8 V
Normalized fanout (each output) 3/	
Case operating temperature range	55° to +125°C

 $[\]overline{\underline{1}/}$ Must withstand the added P_D due to short-circuit test (e.g., I_{OS}). $\underline{\underline{2}}/$ Maximum junction temperature shall not be exceeded except for allowable short duration burn-in screening conditions in accordance with MIL-PRF-38535.

^{3/} Device will fanout in both high and low levels to the specified number of inputs of the same device type as that being tested.

2. APPLICABLE DOCUMENTS

2.1 General. The documents listed in this section are specified in sections 3, 4, or 5 of this specification. This section does not include documents cited in other sections of this specification or recommended for additional information or as examples. While every effort has been made to ensure the completeness of this list, document users are cautioned that they must meet all specified requirements of documents cited in sections 3, 4, or 5 of this specification, whether or not they are listed.

2.2 Government documents.

2.2.1 <u>Specifications and Standards</u>. The following specifications and standards form a part of this specification to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATIONS

MIL-PRF-38535 - Integrated Circuits (Microcircuits) Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard for Microelectronics.

MIL-STD-1835 - Interface Standard Electronic Component Case Outlines

(Copies of these documents are available online at http://assist.daps.dla.mil/quicksearch/ or http://assist.daps.dla.mil or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.3 <u>Order of precedence.</u> In the event of a conflict between the text of this specification and the references cited herein, the text of this document takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

- 3.1 Qualification. Microcircuits furnished under this specification shall be products that are manufactured by a manufacturer authorized by the qualifying activity for listing on the applicable qualified manufacturers list before contract award (see 4.3 and 6.4).
- 3.2 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.
- 3.3 <u>Design, construction, and physical dimensions.</u> The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein.
- 3.3.1 <u>Terminal connections and logic diagrams.</u> The terminal connections and logic diagrams shall be as specified on figure 1.
 - 3.3.2 <u>Truth tables and logic equations.</u> The truth tables and logic equations shall be as specified on figure 2.
- 3.3.3 <u>Schematic circuits</u>. The schematic circuits shall be maintained by the manufacturer and made available to the qualifying activity and the preparing activity upon request.
 - 3.3.4 Case outlines. The case outlines shall be as specified in 1.2.3.
 - 3.4 Lead material and finish. The lead material and finish shall be in accordance with MIL-PRF-38535 (see 6.6).
- 3.5 <u>Electrical performance characteristics</u>. The electrical performance characteristics are as specified in table I, and apply over the full recommended case operating temperature range, unless otherwise specified.

TABLE I. <u>Electrical performance characteristics.</u>

Test	Symbol	Conditions	Device	Lin	nits	Unit
		-55°C ≤ T _C ≤ +125°C	types	Min	Max	
High level output voltage	V _{OH}	$V_{CC} = 4.5 \text{ V}, V_{IN} = 0.8 \text{ V},$ $I_{OH} = -400 \mu\text{A} \underline{1}/$	01, 02, 03, 04, 05	2.4		V
Low level output voltage	V _{OL}	V_{CC} = 4.5 V, I_{OL} = 16 mA, V_{IN} = 2.0 V for all inputs of gate under test $\underline{1}$ /	All		0.4	V
Input clamp voltage	V _{IC}	$V_{CC} = 4.5 \text{ V}, I_{IN} = -12 \text{ mA}$ $T_{C} = 25^{\circ}\text{C}$	All		-1.5	V
Maximum collector cut-off current	I _{CEX}	$V_{CC} = 4.5 \text{ V}, V_{IN} = 0.8 \text{ V},$ $V_{OH} = 5.5 \text{ V}$	06, 07 08, 09		250	μА
High level input current	I _{IH1}	V _{CC} = 5.5 V, V _{IN} = 2.4 V <u>2</u> /	All		40	μА
High level input current	I _{IH2}	V _{CC} = 5.5 V, V _{IN} = 5.5 V <u>2</u> /	All		100	μА
Low level input current	I _{IL}	$V_{CC} = 5.5 \text{ V}, V_{IN} = 0.4 \text{ V} $ 1/	All	-0.7	-1.6	mA
Short circuit output current	I os	V _{CC} = 5.5 V <u>2</u> / <u>3</u> /	01, 02, 03, 04, 05	-20	-55	mA
High level supply current per gate	Гссн	V _{CC} = 5.5 V, V _{IN} = 0 V <u>2</u> /	All		1.65	mA
Low level supply current per gate	I _{CCL}	$V_{CC} = 5.5 \text{ V}, V_{IN} = 5.5 \text{ V}$ 1/	All		5.0	mA
Propagation delay time, high-to-low level	t _{PHL}	$C_L = 50 \text{ pF},$ $R_L = 390\Omega$	01, 02, 03, 04, 05	3	24	ns
			06, 07, 08, 09	3	29	ns
Propagation delay time, low-to-high level	t _{PLH}	$C_L = 50 \text{ pF},$ $R_L = 390\Omega$	01, 02, 03, 04, 05	3	27	ns
			06, 07, 08, 09	3	35	ns

All unspecified inputs at 5.5 volts.
 All unspecified inputs grounded.
 Not more than one output should be shorted at a time.

3.6 <u>Electrical test requirements.</u> The electrical test requirements for each device class shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table III.

TABLE II. Electrical test requirements.

MIL-PRF-38535	Subgroups	(see table III)
test requirements	Class S devices	Class B devices
Interim electrical parameters	1	1
Final electrical test parameters	1*, 2, 3, 9 10, 11	1*, 2, 3, 9
Group A test requirements	1, 2, 3, 9, 10, 11	1, 2, 3, 9
Group B electrical test parameters when using the method 5005 QCI option	1, 2, 3, 9, 10, 11	N/A
Group C end-point electrical parameters	1, 2, 3, 9, 10, 11	1, 2, 3
Additional electrical parameters for group C periodic inspections	N/A	10, 11
Group D end-point electrical parameters	1, 2, 3	1, 2, 3

^{*}PDA applies to subgroup 1.

- 3.7 Marking. Marking shall be in accordance with MIL-PRF-38535.
- 3.8 <u>Microcircuit group assignment.</u> The devices covered by this specification shall be in microcircuit group number 1 (see MIL-PRF-38535, appendix A).

4. VERIFICATION

- 4.1 <u>Sampling and inspection.</u> Sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.
- 4.2 <u>Screening.</u> Screening shall be in accordance with MIL-PRF-38535 and shall be conducted on all devices prior to qualification and conformance inspection. The following additional criteria shall apply:
 - a. The burn-in test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
 - b. Interim and final electrical test parameters shall be as specified in table II, except interim electrical parameters test prior to burn-in is optional at the discretion of the manufacturer.
 - c. Additional screening for space level product shall be as specified in MIL-PRF-38535, Appendix B.

- 4.3 Qualification inspection. Qualification inspection shall be in accordance with MIL-PRF-38535.
- 4.4 <u>Technology Conformance inspection (TCI)</u>. Technology conformance inspection shall be in accordance with MIL-PRF-38535 and herein for groups A, B, C, and D inspections (see 4.4.1 through 4.4.4).
- 4.4.1 <u>Group A inspection.</u> Group A inspection shall be in accordance with table III of MIL-PRF-3853<u>5</u> and as follows:
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, 6, 7, and 8 shall be omitted.
 - 4.4.2 Group B inspection. Group B inspection shall be in accordance with table II MIL-PRF-38535.
- 4.4.3 <u>Group C inspection.</u> Group C inspection shall be in accordance with table IV of MIL-PRF-38535 and as follows:
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. The steady-state life test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
- 4.4.4 <u>Group D inspection.</u> Group D inspection shall be in accordance with table V of MIL-PRF-38535. End-point electrical parameters shall be as specified in table II herein.
 - 4.5 Methods of inspection. Methods of inspection shall be as specified and as follows:
- 4.5.1 <u>Voltage and current.</u> All voltages given are referenced to the microcircuit ground terminal. Currents given are conventional and positive when flowing into the referenced terminal.

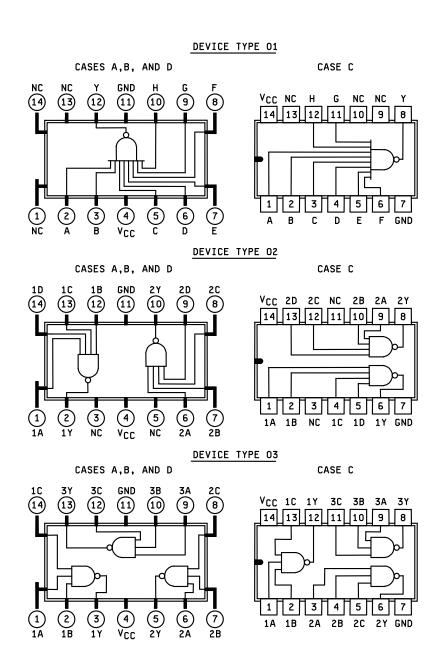
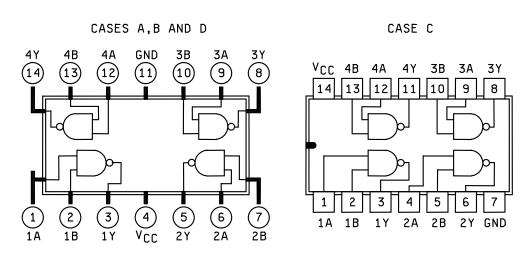


FIGURE 1. Terminal connections and logic diagrams.

DEVICE TYPE 04



DEVICE TYPES 05 AND 08

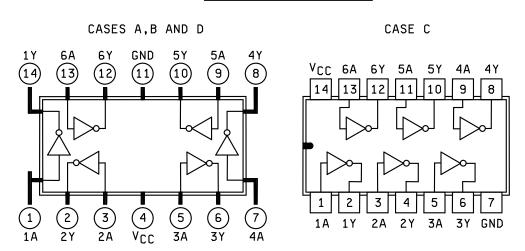
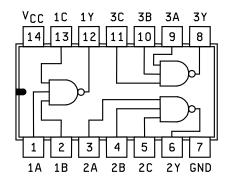


FIGURE 1. <u>Terminal connections and logic diagrams</u> - Continued.

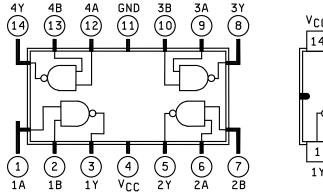
DEVICE TYPE 06 CASES A,B,C AND D

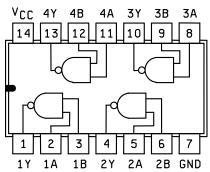


DEVICE TYPE 07

CASES A,B AND D

CASE C





DEVICE TYPE 09 CASE C

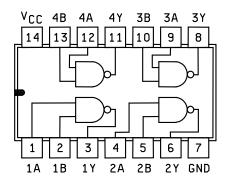


FIGURE 1. Terminal connections and logic diagrams - Continued.

Device type 01

				Truth	ı table					
			Inp	out				Output		
Α	Input	F	G	Н	Υ					
Н	Н	B C D E H H H H	Н	Н	Н	L				
		P	II other	combin	ations o	f H and	L			
			at the	inputs	give H o	output.				

Positive logic Y = ABCDEFGH

Device types 03 and 06

	Т	ruth ta	ble
	Input		Output
Α	В	С	Υ
L	L	L	Н
Н	L	L	Н
L	Н	L	Н
Н	Н	L	Н
L	L	Н	Н
Н	L	Н	Н
L	Η	Н	Н
Н	Н	Н	L

Positive logic Y = ABC

Device type 02

		Device	type uz	
		Truth	table	
	Inp	out	Output	
Α	В	С	D	Υ
L	L	L	L	Н
Н	L	L	L	Н
L	Н	L	L	Н
Н	Н	L	L	Н
L	L	Н	L	Н
Н	L	Н	L	Н
L	Н	Н	L	Н
Н	Н	Н	L	Н
L	L	L	Н	Н
Н	L	L	Н	Н
L	Н	L	Н	Н
Н	Н	L	Н	Н
L	L	Н	Н	Н
Н	L	Н	Н	Н
L	Н	Н	Н	Н
Н	Н	Н	Н	L

Positive logic Y = ABCD

Device types 04, 07, and 09

Tru	th table	e each gate
Inp	out	Output
Α	В	Υ
L	L	Н
Н	L	Н
L	Н	Н
Н	Н	L

Positive logic Y = AB

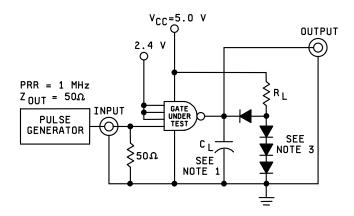
Device types 05 and 08

Truth table	e each gate
Input	Input
Α	Υ
L	Н
Н	L

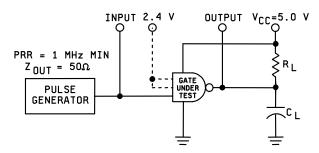
Positive logic Y = A

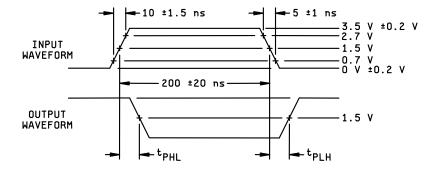
FIGURE 2. <u>Truth tables and logic equations</u>.

TEST CIRCUITS EXCEPT FOR OPEN COLLECTOR CIRCUITS



FOR OPEN COLLECTOR CIRCUITS





NOTES:

- 1. C_L = 50 pF minimum, including scope probe, wiring and stray capacitance, without package in test fixture.
- 2. Voltage measurements are to be made with respect to network ground terminal.
- 3. All diode are 1N3064 or equivalent.
- 4. $R_L = 390 \text{ ohm } \pm 5\%$.

FIGURE 3. Test circuit and switching waveforms.

	its	Max	0.4							-55	40	=	=	=	= :		:	=	=	= :		: :		-1.6	=	= :	: :		5.0	1.65	-1.5	=		-		:		20	25	24
	Limits	Min		2.4		=	=			-20														-0.7		= :												3	3	3
	Measured	terminal	>	>->	- >	- >-	>	>	 -	>	∢ 0	o C	۵ ۵	Ш	LL (თ :	I <	(12	0	ا ۵	ш	ш (υ I	Κ α	o 0	۱۵	ш	-	E >	2)	≪ m	ıO	۵ ۱	υш	. ტ 🗆	E		A to Y	A to Y	> 4 <
14	10	NC																																						Ī
13	6	NC																																						İ
12	80	\	16mA	4mA		=	:	=		GND																												OUT	=	
11	7	GND	GND	GND "		=				GND	GND "				= :		: C	5 =						GND B	=	= :	: :		GND	GND	GND "							GND	=	1
10	12	I	2.0 V	5.5 \	=	=	=	=	. 8.0	GND	GND "	=		=	= :	= 3	2.4 V	5 =		= :		: :	5.5 V	5.5 V	=	= :	: :	= 3	5.5 \	GND						-12 mA		2.4 V	=	
6	11	9	2.0 V	5.5 \	=	=	:	=	0.8 5.5 V	GND	GND "	=		=	=	2.4 \	OND GND	5 =		= :		: 1	5.5 V GND	5.5 V		= :	: :	> 4.0	25.5	GND					-12 mA			2.4 V	=	
8	9	ц	2.0 V	5.5 V	=	=	=	0.8 V	5.5 \	GND	GND	=	=	=	2.4 V	GND "	: U	5 =	=	= :	= [5.5 V	GN=	5.5 \	=	= :	: >	5.5 <	5.5 V	GND				-12 mA				2.4 V	=	
7	2	Е	2.0 V	5.5 \		=	0.8 V	5.5 V		GND	GND "			2.4 V	GND		. C	5 =		=	5.5 V	GND		5.5 V	=	=	0.4 7 4 7) = =	5.5 V	GND			5	-12 mA				2.4 V	=	
9	4	D	2.0 V	5.5 \	=	0.8 \	5.5 \			GND	GND "		2.4 V	GND	=			5 =		2.5 \	GND B			5.5 \	=	0.4 \	> 2.5		5.5 \	GND			-12 mA			I ore omitted	are omitted	2.4 V	=	
2	8	C	2.0 V	5.5 V	780	2.5.5	=	-		GND	GND "	247	GND	=	=			5 =	5.5 V	GND				5.5 \	0.4 V	5.5 V			5.5 \	GND		-12 mA				ا م ۷۰۰ tests	1 Vio tests a	2.4 V	=	
4	14	Vcc	4.5 V	4.5 V	=	=	=			5.5 V	5.5 V	=	=	=	= :		: '4	> ? ?		= :			: :	5.5 \	=	= :	: :		5.5 \	5.5 V	4.5 V	=		=			except Tc = -55°C and Vic tests are omitted	5.0 V	=	
3	2	В	2.0 V	5.5 V	0.05) =)	=	=		GND	GND	7.4 GND	=	=	= :		: U	5.5 \	GND	= :		: :		5.5 V	5.5 \	= :	: :		5.5 V	GND	-12 mA	!				avcent Tc	except To	2.4 V	=	
2	-	Α	2.0 V	0.8 V	> 0. =	=	=	=		GND	2.4 V	<u> </u>	=	-	=		: 4	GND	=	= :			: :	0.4 V	>) =)	= :			5.5 V	GND	-12 mA							Z N	=	
1	13	NC																																		I imite as for	imits as for			
Cases A, B, D	Case C	Test no.	_	2 0	o 4	- 40	9		ထ တ	10	11 6	<u>4 6</u>	5 4	15	91	17	18	20	21	22	23	24	72 76 76	27	78	30	37	33.8	35	36	37	36	04.4	42	. 64	Same fests ferminal conditions and limits as for subgroup	Same tests terminal conditions and limits as for subgroup	45	46	,
<u>-</u>	883	method	3007	9008						3011	3010						2040	2						3009					3005	3005						L terminal c	terminal c	3003	(Fig. 3)	
	Symbol		Vol	V _{ОН}						sol	1111							Ž						_=					Ē	3 5	N _{IC}					Same tests	Same tests	t _{PHL}	t _{PLH}	
	group		_	= 25°C																																2	1 K	6	= 25°C	i

TABLE III. Group A inspection for device type 02.	ninal conditions (pins not designated may be high $\geq 2.0 \text{ V}$, low $\leq 0.8 \text{ V}$ or open)
---	--

	Unit		>=	>=				"	mA "	μΑ "				: =	Ψ.	=				mA "	=		: :		mA	mA	>:::						us •	ns "	ns "	us "	
	its	Max	0.4						-25	40		: :			100	=				-1.6					10	3.3	5.1-						50	25	24	27	
	Limits	Min		2.4		=		=	-20											-0.7	=												က =	က =	es =	က =	
	Measured	terminal	7, √	≿ ≿	≿ ₹	- 5	5 ₹	2Y	1Y 2Y	4 4	5 5	24 TD	38 S	22	ξ	5	1D V	2B 2B	2C 2D	41 4	5	- 2	28 A	325	22/2		¥ # 2	5 5	78 78	22			1A to 1Y 2A to 2Y	j			
11	2	10	2.0 V 5.5 V	5.5 V	= 0	5.5 V		=	QND	GND	=	2.4 V GND	: =	: =	GND B	=	5.5 V	<u> </u>		5.5 V	=	0.4 \	> 2.5		5.5 V	GND		-12 mA					2.4 V	2.4 V	2.4 V	2.4 V	
13	4	10	2.0 V 5.5 V	5.5 \	0.8 \	> ?:			GND	GND "	2.4 V	GND "		: =	GND "	5.5 V	GND B	=		5.5 V	0.4 V	5.5 V	: =		5.5 V	GND	-12 mA						2.4 V	2.4 V	2.4 V	2.4 V	
12	2 2	18	2.0 V 5.5 V	5.5 V 0.8 V	5.5 \			"	GND	GND	GND			: :	GND	GND				5.5 V	5.5 V				5.5 V	GND	-12 mA						2.4 V	2.4 V	2.4 V	2.4 V	
10 v or operio	7	GND	GND	GND					GND	GND "				: =	GND "					GND "	=				GND	GND	GND 					4110	GND -	GND	GND "	GND	7
, o	2 &	27	16 mA			4 mA			GND								-													•	-		DOUT	OUT	OUT	TUO	
	13	2D	5.5 V 2.0 V	5.5 V				0.8 V	GND	GND "	=			2.4 V	GND "	=			5,5 \	5.5 V	=		: =	. 5	5.5 V	GND				-12 mA			2.4 V	2.4 V	2.4 V	2.4 V	
α Σ	12	2C	5.5 V 2.0 V	5.5 V			> 80	5.5 V	GND	GND "			= ;	2.4 V GND	GND "	-		-	5.5 V GND	5.5 V	-			V 4.0	5.5 V	GND				-12 mA			2.4 V	2.4 V	2.4 V	2.4 V	
7	10	2B	5.5 V 2.0 V	5.5 \			0.8 \	. =	GND	GND "			2.4 \	O =	GND "	-		5.5 V	GND "	5.5 V	-		. 7 0	5.5 \	5.5 V	GND			-12 mA				2.4 V	2.4 V	2.4 V	2.4 V	
101 G	0	2A	5.5 V 2.0 V	5.5 \		0.8 V	5.5 \		GND	GND "	-	2.4 \	QND CIND	: =	GND -	-	= v	GND		5.5 V	-	= ;	0.4. 7.7.) = =	5.5 V	GND		200	X		c tests are omitted	are omitted.	Z	Z	Z	Z	-
SI G	7 -	NC																												-	d V _{IC} tests	V C tests	5.0 V "				-
	- 41	Vcc	4.5 V	4.5 V					5.5 V ".	5.5 V "					5.5 V					5.5 V	=		: =		5.5 V	5.5 V	4.5 \				= 125°C and V	= -55°C and	5.0 V	5.0 V	5.0 V	5.0 V	c = -55°C.
	n (n	NC																													, except Tc =	, except Tc					0, except T
c	9	7	16 mA	4 mA "					GND																						subgroup 1	subgroup 1	DOUT	DUT	OUT	TUO	subgroup 1
-	- -	14	2.0 V 5.5 V	0.8 V 5.5 V					GND	2.4 V GND	=				5.5 V GND	=		-		0.4 V	>) =)				5.5 V	GND	-12 mA				mits as for:	mits as for	Z	Z	Z	Z	mits as for
In a v sessol at S IIM	Case C	Test no.	7 2	κ 4	ro u	۸ م	<u></u> დ თ	10	11	13	<u>.</u> 5	16	: & 6	20	21	73 23	24	7 7 8	27	29	3.5	32	£ 8	32	37	38	39 40 41	45	5 4 4	45 46	Same tests, terminal conditions and limits as for subgroup 1	Same tests, terminal conditions and limits as for subgroup 1, except Tc	47	49 50	51 52	53	Same tests, terminal conditions and limits as for subgroup 10, except Tc
VIII CTD	883	method	3007	3006					3011	3010					3010					3009					3005	3005					, terminal c	s, terminal c	3003 (Fig. 3)	3003 (Fig. 3)	3003 (Fig. 3)	3003 (Fig. 3)	s, terminal c
	Symbol		Nor	Мон					sol	IH4					IH2					=					2	13 <u>18</u>	o /				Same tests	Same tests	ᄩ	tp.H tp.H	t _{PHL}	te te	Same test
	Subgroup		1 Tc = 25°C																														9 Tc = 25°C		10 Tc = 125°C		7

Tem	nina	TA conditions	(BLE III	<u>a</u>	oup 4	\ insp	ection may b	oe hiv	devic	e typ	e 03.	× 0.8	V or	open)		TABLE III. Group A inspection for device type 03.	Terminal conditions (pins not designated may be high > 2.0 V, low < 0.8 V or open)
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	Unit		>=	=	>=			:	= :		m.		Αij.		=		= :		: =	Α'n.	-	=		: :	=		m,	=			-	= :	. 4	¥,	mA	>=	=	=		: =			
	its	Max	0.4	=							-55		40	=	=	=	= :		: =	100	-	=	=	: :	=	=	-1.6	=			-	Ξ :		CE. 1	15	. -	=	=		: =			
	Limits	Min			2.4	= :		=	= :	::	-20	: :															2.0-	=	=		=	= :	:										
	Measured	terminal	17 27	37	≿ ≿	;	5,√	24	37	3,≼	٦٢ (3 ≾	1A	<u>5</u>	2A	2B	SC.	3A	3C 8	4;	<u> </u>	2 - S	2B	2C	3B	3C	1A 15	<u>5</u>	2A	2B	ر م	3B	ر د	vcc	Vcc	₹ ₩	<u>;</u> 6	2A	2B	3 S C	3B	ر د	
77	13	10	2.0 V 5.5 V	=	5.5 <	0.8 V	2.5 \	=	= :		GND		GND "	2.4 V	GND	=	= :		: =	GND	7 2 7	GND	=		=	=	5.5 V	0.4 V	5.5 V			= :	: [GIND	5.5 V		-12 mA						
40	2 &	37		16 mA					4 mA			GND																															
peri)	1 =	30	5.5 V	2.0 V	5.5 \			=	= :	. 8.0		GND	GND "	=	=		= :		2.4 \	GND		=	=		=	5.5 V	5.5 V	=	-			=	0.4 V	OND I	5.5 V							HII 71-	
o. 2		GND	GND	=	GND B			=	= :		GND		GND "	=	-	-	= :		: =	GND	=				=	-	GND "		=			= :	: 2	GIND	GND	GND B	=	-					
, low /	10	38	5.5 V	2.0 V	5.5 \			-	=	0.8 5.5 V		GND	GND "	=	=		= :	= ;	2.4 V GND	GND "		=	-		5.5 \	GND	5.5 V "	=	-			0.4 V	2.5 \	ON S	5.5 V						-12 mA		
V 0.2 ≥ I	0	34	5.5 V "	2.0 V	5.5 \			-	0.8 V	5.5 \		GND	GND "	-	=	=	=	2.4 \	ם =	GND	=	=	=	- V	S.S.	=	5.5 V	=	-		0.4.V	5.5 \	: Q	GIND	5.5 V					-12 mA			
y be iligi	2	2C	5.5 V 2.0 V	5.5 V	5.5 \	= :		0.8 V	5.5 V			QND	GND	=	=	=	2.4 V	GND B	: =	GND		=	=	5.5 V	<u> </u>	=	5.5 V	=	=	= 3	V 7 7 7 7 7 7 7 7 7 7 7 7 7 7 7 7 7 7 7) = :	: 2	GIND	5.5 V				,	-12 mA			
alen IIIa	. 4	2B	5.5 V 2.0 V	5.5 V	2.5 \		- ×	5.5 \	= :			GND	GND "	=	-	2.4 V	GND		: =	GND		-	5.5 V	GND B	=	-	5.5 V		=	V 4.0	> 0.0	= :	: 2	GIND	5.5 V				-12 mA				
or design	e e	2A	5.5 V 2.0 V	5.5 V	> 2.5 <	= ;	0.8 \	> =	=			GND	GND "	=	2.4 V	GND	= :		: =	GND "		5.5 V	GND		=		5.5 V	-	0.4 V	5.5 \		= :	: [GIND	5.5 V			-12 mA				7	re omitted.
ll silld) s	9	2	16 mA				4 mA "	=			!	GND													-																	- 1	V _{IC} tests a
CUTURIORIS (PINSTIDI DESIGNACEU INAY DE INUN Z C.O V OL OPEN	- 41	Vcc	4.5 V	=	4.5 V	= :		=	= :		5.5 V		5.5 V	=	-	=	= :		: =	5.5 V		=	-		=			-	=	= =	-	= ;	: 4	2.0.0	5.5 V	4.5 \	-			: =		00007	125°C and
ellilla °	12		16 mA	\dashv	4 mA "						GND																															_ F	except 1c -
	2 2	18	2.0 V 5.5 V	\dashv	5.5 \			=	= :		GND		GND	GND GND	=	=	= :		: =	GND	2.5 V CN C	} =	=		=	=	5.5 V	5.5	=			= :	: 2	GIND	5.5 V	-12m4						1	nagroup 1,
·	- -	14	2.0 V 5.5 V	=	0.8 <			-	=		GND		2.4 \	<u> </u>	-		= :		: =	5.5 V	۵ = و	=	-		=		0.4 V	> ? :	=			= :	: 2	GIND	5.5 V	-12 mA							Alts as ior s
La d A soco A CTS IIM	Case C	Test no.	- 2	3	4 rc	9 9 1	~ 8	ე თ	10		13	4 5	16	- 8	9 6	20	21	22	24.3	25	270	78	59	30	32	33	34	98	37	88 8	39	2 4	42	54			47	48	49	5.00	25	50	Same tests, terminal conditions and limits as for subgroup 1, except 1 c = 125°C and V _{1,C} tests are omitted conditions and limits as for subgroup 1, except 1c = 155°C and V ₁ tests are omitted
OTO IIM	883	method	3007		3006						3011		3010							3010							3009						3006	2002	3005								S, Terminal
	Symbol		Vol		V _{OH}						sol		표							IH2							ᅰ						<u> </u> -	¥8.	CCL	راد \							Same tests
	Subgroup		1 Tc = 25°C																																								7 6

			Limi	Min	3			က			3			3			
			ъ			_			_	,		_	_		_	,	
			Measured	terminal	1A to 1Y	2A to 2Y	3A to 3Y	1A to 1Y	2A to 2Y	3A to 3Y	1A to 1Y	2A to 2Y	3A to 3Y	1A to 1Y	2A to 2Y	3A to 3Y	
		14	13	10	2.4 V			2.4 V			2.4 V			2.4 V			
		13	8	37			OUT			OUT			OUT			OUT	
	oben)	12	11	3C			2.4 V			2.4 V			2.4 V			2.4 V	
led.	J.8 V or 0	11	7	GND	GND			GND			GND			GND			
· Continu	/, low ≤ (10	10	38			2.4 V			2.4 V			2.4 V			2.4 V	
type 03 -	h ≥ 2.0 \	6	6	3A			z			Z			z			Z	
TABLE III. Group A inspection for device type 03 - Continued.	Terminal conditions (pins not designated may be high ≥ 2.0 V, low ≤ 0.8 V or open)	8	2	2C		2.4 V			2.4 V			2.4 V			2.4 V		
ection fo	nated ma	7	4	2B		2.4 V			2.4 V			2.4 V			2.4 V		
p A insp	ot desig	9	3	2A		Z			Z			Z			z		
III. Grou	ıs (pins r	2	9	2Y		DOUT			DOUT			DOUT			TUO		
TABLE	condition	4	14	Vcc	5.0 V	:		5.0 V			5.0 V	:		5.0 V			c = -55°C.
	erminal	3	12	1	DUT			TUO			TUO			TUO			0, except To
		2	2	1B	2.4 V			2.4 V			2.4 V			2.4 V			subgroup 1
		1	-	1A	Z			Z			Z			Z			imits as for
		MIL-STD-Cases A, B, D	Case C	Test no.	54	22	26	57	28	59	09	61	62	63	64	65	Same tests, terminal conditions and limits as for subgroup 10, except $Tc = -55^{\circ}C$.
		-GLS-TIW	883	method	8008	(Fig. 3)		3003	(Fig. 3)		8008	(Fig. 3)		3003	(Fig. 3)		ts, terminal
			Symbol		t _{PHL}			t _{PLH}			t _{PHL}			tP∟H			Same tes:
			Subgroup Symbol		6	Tc = 25°C					10	Tc = 125°C					11

S = =

S = =

Max 20

S = = S = =

24

spection for device type 04.
Group A in:
TABLE III.

		Onit		>=		>=		=		-	=	Ψ.		Αų.		=		=	=	Ψ'n		-	=			mA"					mA	mA	>						
		its	Max	4."								-22		40						100		-				-1.6					9.9	20	-1.5						
		Limits	Min			2.4	-	=		-	=	-20														-0.7	-												
		Measured	terminal	, ∠	3 ,	<u></u>	5 -	27	3,≺	3. ∀ ¥	47	5 4	7 ₹	4,	1B 2A	2B	3A	3B 4	4 4 B	14	1B	2B 2B	3A	3B	4 4	14 18	2 A 2	2B	3B	4 4 g	۲ ₂	N _{CC}	1A	1B 2	28 2B	3A 3B	4 t	40	
	14	11	4Υ		16 mA					- 4 mA			GND																										
	13	13	4B	5.5 \	2.0 \	5.5 V		= :			0.8 V		GND	GND "	: :				2.4 V	GND					5.5 V	5.5 V				: 5	GND	5.5 V					(-12 MA	
pen)	12	12	4A	5.5 \	2.0 \	5.5 V		= 1		> 8 0	5.5 V		GND	GND "	: :	=			QND CHO	GND				= 4	OND CND	5.5 V			: =	0.4 V	GND	5.5 V					-12 mA		
0.8 V or open)	11	7	GND	QND B		GND "	:	= :		:		QND B		GND "	: :			: =		GND		=			:	GND "			: =		GND	GND	GND						
. 🗸		10	3B	5.5 \	2.0 V 5.5 V	5.5 V	:	= :	= 0	5.5 <			GND	GND "	: =	=	= 3	2.4.V	=	GND		=		5.5 V	 	5.5 V			V 4 V	5.5 \	GND	5.5 V				7 P	<u> </u>		
	6	6	3A	5.5 \	2.0 V 5.5 V	5.5 V	=	=	0.8 \	> o =			GND	GND "	: =	=	2.4 \			GND		=	5.5 V	GND =	=	5.5 V ".		= 3	5. 7. 5. 7. 5. 7.		GND	5.5 V				-12 mA	•		
oroup A inspection for device type 04 of designated may be high ≥ 2.0 V, low	8	80	3У		16 mA				4 mA "				GND									-																	
ated may		2	2B	5.5 V 2.0 V	2.5 \	5.5 V			. 2.5 \		=	GND		GND	: :	2.4 V	GND :	: =		GND		5.5 V	GND		-	5.5 V		0.4 V	> 0.0		GND	5.5 V			-12 mA				
design:	9	4		5.5 V 2.0 V		5.5 V		5.5 V		-		OND		GND												5.5 V					+	5.5 V		-12 m4				7 - 177	omitted.
I ABLE III. ons (pins no	2	9		16 mA			4 mA					GND															_												or tests are ornitted to the condition of the condition o
conditions (pins not designated may be high ≤	4	14	Vcc			75.1		=		-	=			.5 V	: =	-				.5 V		=	-		=	5.5 V			: =		.5 V	.5 V	4.5 V		-			- 000	Safire tests, terminal conditions and minis as for subgroup 1, except 1c = 123 C and V _{1C} tests are omitted Same tests, terminal conditions and limits as for subgroup 1, except TC = -55°C and V _{1C} tests are omitted
Terminal co	3	9		16 mA 4		4 mA						GND		4)						47		-				4)					4,	4)	4		-			-	cept Ic = 1
Tel	2	2		2.0 V 5.5 V		5.5 V		-				GND		GND	> CN	=				GND	> 5.5				-	5.5 V	. > .				QNS	5.5 V		-12mA				-	group 1, ex group 1, ex
	_			2.0 \ 5.5 \ 5		0.8 V				_		GND		2.4 V G		_				5.5 V G			_		_	0.4 V 5					+	5.5 V 5	_	<u>-</u>					as for sub
	B, D			. 67		0.4		-														-																1 1 1	s and limits s and limits
	MIL-STD-Cases A, B, D		Test no.	- 0	ω 4	ı,	^ 0	ω	σ (2 = =	12	£ 4	15	17	2 6	20	22	22 62	242	25	26	78	29	30	32	33	35	36	38	38	4 4	42	43	44	46	47	49	nc	conditions conditions
	MIL-STD	883	method	3007		3006						3011		3010						3010						3009					3005	3005							sts, termina sts, termina
		Symbol		Nor		V _{он}						sol		-H						I _{HZ}						_=					-5	8 8	ر داد						Same tes
		Subgroup		1 Tc = 25°C																																		c	3 8

		H	_	_	_	_		H	_	_	_	_	_	_	-	H	_	_	_	
		Limits	Max	20	=	-	=	22	=	=	=	24	=	=	=	27	=	=	=	
		Lim	Min	3	=	=	=	က			=	3			=	က	=		=	
		Measured	terminal	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	
	14	13	47				OUT													
	13	8	4B				2.4 V													
open)	12	11	4A				Z				Z				Z				Z	
led. 0.8 V or	11	7	GND	GND	:	:	=	GND	:			GND		=	=	GND				
TABLE III. Group A inspection for device type 04 - Continued. Terminal conditions (pins not designated may be high $\geq 2.0~\text{V}$, low $\leq 0.8~\text{V}$ or open)	10	10	3B			2.4 V														
type 04 th ≥ 2.0 \	6	6	3A			Z				Z				Z				Z		
r device ay be hig	8	2	37			OUT				DOT				DOT				DOT		
ection for	7	4	2B		2.4 \				2.4 \				2.4 V				2.4 V			
up A insp not desig	9	3	2A		Z				Z				Z				z			
III. Grouns III.	2	9	27		TUO															
TABLE condition	4	14	Vcc	5.0 V				except Tc = -55°C.												
Ferminal	3	12	17	OUT				DUT				OUT				DUT				0, except T
'	2	2	18	2.4 V				subgroup 1												
	1	1	1A	Z				Z				Z				Z				imits as for
	MIL-STD- Cases A, B, D	Case C	Test no.	51	25	23	24	55	26	22	28	26	09	61	62	63	64	92	99	Same tests, terminal conditions and limits as for subgroup 10,
	MIL-STD-	883	method	3003	(Fig. 3)			ts, terminal												
		Symbol		t _{PHL}				t _{PLH}				t _{PHL}				t _{PLH}				same tes

Unit

S = = = | S = = = | S = = =

10 Tc = 125°C

9 Tc = 25°C

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	obe
	8 V or
	0.8
5	∨I >
oe 0	$0.0 \text{ V, low} \le 0.8$
e tyr	2.0 V, low s
or device type	2 ا
or d	hig
on f	y be
ecti	ma
insp	ated
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TABLE III. Gro	(pins not designated may be high ≥
TABLI) suc
	ditic
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	inal conditions (
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	Ħ											4			-		4					,					<					d	۵							
	Unit		> =	-	_		>	_	-	-		hm.													_						4					-	-	4		
	Limits	Max	0.4	=	-							-25	-		= :	=	40		-	-	=	100		-	-	=	-1.6	-	=		=	30	6.6	-1.5	-	=				
	Lir	Min					2.4		: =	=	=	-20	=	=	= :	=											-0.7		=	=	=									
	Measured	terminal	۸۲	- X:	₹	<u></u> 2√	; \	5₹	} }	- 75	, A9	1Y 2V	3 7	. 4	2√	К9	1A 2.	5 A	ς γ Υ Υ	Z Y	. 6A	41 80	7 A	A A	5A	6A	1A 20	3 K	4A	5A	6A	Vcc	V _{CC}	4 €	3 K	44 4	24 24	Yo		
14	2	6A	16mA				4mA					GND																												
13	13	6У	5.5 V		-	2.0 <	5.5 V			-	0.8 V				!	GND	GND		-	=	2.4 V	GND		-	-	5.5 V	5.5 V		=		0.4 V	5.5 V	GND				5	-12 IIIA		
12	12	6У				16mA					4 mA				!	GND																								
-	7	GND	GND "	=			GND		: =		=	GND "			= :		GND	: :				GND "	: :				GND "				=	GND	GND	GND B						
10	10	57				16mA				- 4 mA					GND																									
9	1	5A	5.5 V	=	=	2.0 \	5.5 V		: =	> 8 0	5.5 V				GND		GND	: :	:	247	GND	GND "	: =	=	5.5 V	GND	5.5 V	=	:	0.4 V	5.5 V	5.5 V	GND				-12 mA			
^	8				16mA				2					GND																										
7	6	4A	5.5 V	=	2.0 V	5.5 \	5.5 V		: 0	2 2 2	• • •			GND			GND	: :	7.0	- CN	=	GND "	: =	5.5 \	QND CSND	=	5.5 V	=	0.4 V	5.5 V	=	5.5 V	GND			-12 mA				
9	9	37		16mA					4 mA				GND	!																								7.7	are omitted.	re omitted.
2 2	2	3A	5.5 V	> 0 <	5.5 \		5.5 V	= 0	> 20 4		=		GND	1			GND	: 7	> C	5 =	=	GND "		OND OND] =		5.5 V	V 4 V	5.5 \	=	=	5.5 V	GND		-12 mA	!		- 1	125°C and V _{IC} tests are omitted	1 V _{IC} tests a
4	14	Vcc	4.5 V	=	=	> 9.0	4.5 V			=	=	5.5 V "	=	=	= :		5.5 V	: -		=	=	5.5 V		-	=		5.5 V	=	=	=	=	5.5 V	5.5 V	4.5 \	=	=		4000	= 125°C an	= -55°C and
8	3	2A	5.5 V	> 2. 7.			5.5 V	0.8 > 1	۲. ۲. د	=		CND	2				GND	> 4.2	<u> </u>	=		GND	رن ر ا در ا	<u> </u>	=		5.5 V	5.5			=	5.5 V	GND	2	X			F	, except I c	, except Tc
2	4	2Y	7 50	<u>{</u>				4 mA				CND																											limits as for subgroup 1, except 1c =	. dnoubgns
-	11	1A	2.0 V	> :	=		0.8 V	5.5 \				GND					2.4 V	ON P	:		-	5.5 V	O =	-	-		0.4 V	> :			=	5.5 V	GND	-12 mA					imits as for	limits as for
MIL-STD- Cases A, B, D	Case C	Test no.	← c	v 65	. 4	o 2	7	∞ (D 5	2 = =	12	13	<u> </u>	16	17	18	19	2 50	- 60	33 23	24	25	26	28	73	30	31	33.2	34	35	36	37	38	39	0 4 4	4.5	43	444	same tests, terminal conditions and	Same tests, terminal conditions and limits as for subgroup 1, except Tc =
MIL-STD-	883	method	2008				3006					3011					3010					3010					6008					3005	3005						s, terminal c	s, terminal c
	Symbol		Nor				V _{ОН}					sol					lH1					I _{H2}					11					5	-BCH	<u>ာ</u>					ame test.	ame test.
	Subgroup		1 020	O-6Z = 21			1																															Ť	2	

				Max	20						25	-					24	=			-		27	-				=
			Limits	Min	3	-	_	_	_	_	3	_	_	_	_	_	3	-	-		-		3	-	-	-	_	-
			р			_	_	_	_	_	L	_	_	_	_		_	_	_	_	_	_		_	_	_	_	_
			Measured	terminal	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	5A to 5Y	6A to 6Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	5A to 5Y	6A to 6Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	5A to 5Y	6A to 6Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	5A to 5Y	6A to 6Y
		14	13	44	OUT						OUT						TUO						OUT					
		13	8	4B						Z						N						z						Z
	pen)	12	11	4A						OUT						OUT						OUT						OUT
ed.	erminal conditions (pins not designated may be high $\geq 2.0~\text{V}$, low $\leq 0.8~\text{V}$ or open)	11	7	GND	GND	:				-	GND	-			-	=	GND	=					GND	=				=
Continu	$\log v \leq 0$	10	10	3B					DOT			_			DOT						TUO						DOLT	
ype 05 -	$1 \ge 2.0 \text{ V}$	6	6	3A					z			_			z						z	-					z	
TABLE III. Group A inspection for device type 05 - Continued.	y be high	8	2	3У			_	TUO				_		TUO						DUT						TUO		
ction for	ated ma	7	4	2B				z						z						z						z		
A inspe	t design	9	3	2A			TUO						OUT						OUT						OUT			
Sroup	ns no											_	_		_	_												
<u>≡</u>	ins (pi	2	9	2Y			Z						Z						Z						Z			
TABLE	l condition	4	14	V _{CC}	2.0 V		=	=	=	=	2.0 V	:	=	=	=	=	2.0 V			-		=	5.0 V	=	:	=	=	=
	Termina	3	12	17		Z						Z						Z						Z				
		2	2	1B		OUT						DOLT						DUT						DOT				
		1	1	1A	Z						Z						Z						z					
		MIL-STD- Cases A, B, D	Case C	Test no.	45	46	47	48	49	20	51	52	53	54	55	26	25	28	29	09	61	62	63	64	65	99		89
		MIL-STD-	883	method	3003	(Fig. 3)					3003	(Fig. 3)					3003	(Fig. 3)					3003	(Fig. 3)				
			Symbol		tpHL						t _{PLH}						t _{PHL}						t _{PLH}					
			Subgroup Symbol		6	Tc = 25°C											10	Tc = 125°C										

Same tests, terminal conditions and limits as for subgroup 10, except $Tc = -55^{\circ}C$.

6 3 4 2Y 2A 2B				
5A		14	12	
ł				
16 mA 2.0 V 5.5 V 5.5 V 5.5 V 5.5 V 5.5 V	4.5 \	6.5	9 m A	2.0 V 16 mA 5.5 V
+	4.5 V	4.5	.5 V	+
				0.8 V 7 7 7 7
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77				
-12 mA		= :		
GND GND	5.5 V	5.5		0
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2.4 V		= :	-	
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5.5 V 5.5 V	5.5 V	5.5		5.5 V
	5.5 V	5.5		ll

			S	Max	23	=		28	=		58	=		35	=			
			Limits	Min	3	=	=	က		=	3		-	က		=		
			Measured	terminal	1A to 1Y	2A to 2Y	3A to 3Y	1A to 1Y	2A to 2Y	3A to 3Y	1A to 1Y	2A to 2Y	3A to 3Y	1A to 1Y	2A to 2Y	3A to 3Y		
			13	10	2.4 V			2.4 V			2.4 V			2.4 V				
			80	Ж			DOL			OUT			DOL			OUT		
	oben)		7	3C			2.4 V			2.4 V			2.4 V			2.4 V		
ed.	.8 V or 0		7	GND	GND	:	=	GND	=	:	GND		=	GND		:		
· Continu	/, low ≤ (10	38			2.4 V			2.4 \			2.4 V			2.4 \		
TABLE III. Group A inspection for device type 06 - Continued.	h ≥ 2.0 \		6	3A			Z			z			z			z		
r device	ay be hig		2	2C		2.4 V			2.4 V			2.4 V			2.4 V			
ection fo	nated ma		4	2B		2.4 V			2.4 V			2.4 V			2.4 V			
p A insp	ot design		ო	2A		z			z			z			z			
III. Grou	s (pins n		9	27		TUO			TUO			TUO			TUO			
TABLE	erminal conditions (pins not designated may be high $\geq 2.0~V,$ low $\leq 0.8~V$ or open)		14	Vcc	5.0 V			5.0 V			5.0 V		:	5.0 V			except Tc = -55°C.	
	erminal		12	1	OUT			DUT			OUT			DUT), except To	
	_		2	18	2.4 V			2.4 V			2.4 V			2.4 V			subgroup 1	
			_	1A	Z			z			Z			Z			mits as for	
		MIL-STD- Cases A, B,	C, and D	Test no.	51	25	53	54	22	26	25	28	29	09	61	62	Same tests, terminal conditions and limits as for subgroup 10,	
		MIL-STD-	883	method	3003	(Fig. 3)		3003	(Fig. 3)		3003	(Fig. 3)		3003	(Fig. 3)		s, terminal o	
			Symbol		t _{PHL}			t _{PLH}			t _{PHL}			t _{PLH}			Same test	
			Subgroup Symbol		6	Tc = 25°C					10	Tc = 125°C					11	

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	Limits	Max	0.4		250		=				40		-				100	=				: =		-1.6						20	9.9	-1.5		-			=
	Ė	Min																						-0.7		-	-	-									_
	Measured	terminal	1Y 2Y	¥ 4	∤	<u>-</u> ≿	24	37	34	4 4 Y ≻	4 t	3 P	2 Z	34 8	3B	4 t	4P	18	2A	2B	3A	SB A	4 4	₹;	2 c	7 Z	3 E	3B	4 t	ر دی ک	>>	₹ ;	1B 2A	3B	3A	4 % 8 4	4B
14	13	4		16 mA						> 2.5																											
13	12	4B	Λ 5''5	2.0 \	5.5 V		=	=	= 1	4.5 V 0.8 V	GND		=	=		= ?	GND	=	=	=		: =	5.5 V	5.5 V		=	=	=	- 7	5.5 V	GND						12m
12	11	4A	2.5 V	2.0 \	5.5 V		=	=	= (0.8 V 4.5 V	GND		=	=		2.4 \	GND	=	=	=		7 2 7	GND	5.5 V		=	=	=	0.4 \	5.5 V	GND					-12mA	
11	7	GND	GND		GND "		=			: :	GND		=	=			GND	=	=					GND		=	=			GND	GND	GND				: :	=
10	6	3B	5.5 V	2.0 V 5.5 V	5.5 V		-	4.5 V	0.8 \	5.5 \	GND		=	-	2.4 V	GND B	GND	=	-	=	= [5.5 V C.G	<u> </u>	5.5 V		=	-	0.4 V	5.5 \	5.5 V	GND					-12mA	
6	8	3A	5.5 V	2.0 \	5.5 V	=	-	0.8 V	7:5	> 5.5	GND "		-	2.4 V	GND		GND	=	-	-	5.5 V	O =	=	5.5 V		-	0.4 V	5.5 V		5.5 V	GND				-12mA		
8	10	3Y		16 mA				5.5 V	=																												
7	9	2B	5.5 V 2.0 V	5.5 \	5.5 V	7 2 7	0.8 \	5.5 V		: :	GND "	: =	247	GND	=		GND	=	=	5.5 V	GND END	: =	=	5.5 V		0.4 \	5.5 V	=		55 V	GND			-12mA			_
9	2	2A	5.5 V 2.0 V	5.5 \	5.5 V	> 8 0	4.5 \	5.5 V		: :	GND "	247	J. C] =	-		GND	=	5.5 V	GND				5.5 V	: ?	5 5) = ;	=		5.5 V	GND		-12mA				_
5	4	2Y	16 mA			75.7) =																														
3 4 5 6 7 8 9 10	14	Vcc	4.5 V		4.5 V	-	=	=	= :	: =	5.5 V		=	=			5.5 V) =	=	=			=	5.5 V		=	=	=		5.5 V	5.5 V	4.5 V	: :	=		: =	-
3	1	1Y	16 mA		5.5 V "																																
2	3	1B	2.0 V 5.5 V		4.5 V	> 20. 10.) =)			: :	GND	2.4 V GND	5 =	=	=		GND	5.5 V	GND	=				5.5 V	V 4.0	> =	=	=		5.5 V	GND		-12mA				
1	2	1A	2.0 V 5.5 V		0.8 V	4. rc 5. rc 5. xc) =)	=			2.4 V	ON F	=	-	-		5.5 V	GND	-	=			=	0.4 V	> 2.5	=	-	=		5.5 V	GND	-12mA					_
MIL-STD- Cases A, B, D	Case C	Test no.	1 2	ω 4	5	9 1	- 00	6	10	12	13	4 t	5 6	17	18	19	21	22	23	24	25	26	28	29	30	32	33	34	35	37	38	39	40 41	. 24	43	44 45	310
MIL-STD-	883	method	3007								3010						3010	2						3009						3005	3005						_
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	Subgroup		1 Tc = 25°C																																		

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TABLE III. 0	

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		Limits	Max	23	=			78	=	=		53				32				
		ŗ	Min	3	=			က	=	=		3				က				
		Measured	terminal	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	
	14	13	47				DUT				TUO				DUT				TUO	
	13	12	4B				2.4 V				2.4 V				2.4 V				2.4 V	
oben)	12	11	4A				Z				Z				Z				Z	
0.8 < 05	11	7	GND	GND				GND	=			GND				GND				
^, IOW ^	10	6	38			2.4 V				2.4 V				2.4 V				2.4 V		
n ≥ 2.0	6	8	3A			z				z				z				z		
ay be nıç	8	10	3У			DUT				DUT				DUT				DUT		
nated ma	7	9	2B		2.4 V				2.4 V				2.4 V				2.4 V			
iot desig	9	2	2A		Z				Z				Z				Z			
erminal conditions (pins not designated may be nign $\geq 2.0 \text{ V}$, low $\leq 0.8 \text{ V}$ or open	2	4	2Y		TUO				TUO				DOUT				OUT			
condition	4	14	Vcc	2.0 V				5.0 V				5.0 V		:		5.0 V		:		c = -55°C.
erminal	3	-	1	OUT				DUT				OUT				DUT				0, except T
	2	3	18	2.4 V				2.4 V				2.4 V				2.4 V				subgroup 1
	1	2	1A	Z				Z				Z				Z				imits as for
	MIL-STD-Cases A, B, D	Case C	Test no.	47	48	49	20	51	52	23	54	22	26	22	28	29	09	61	62	Same tests, terminal conditions and limits as for subgroup 10, except Tc
	MIL-STD-	883	method	3003	(Fig. 3)			3003	(Fig. 3)			3003	(Fig. 3)			3003	(Fig. 3)			ts, terminal
		Symbol	_	ПН⊲		_	_	t _{PLH}	_	_	_	⊓нdį		_	_	t _{PLH}		_	_	Same tes
		Subgroup Symbol		6	Tc = 25°C							10	Tc = 125°C							11

Group A inspection for device type 08.	
TABLE III.	. ,

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2.0 V | 5.5 V

 | | : = | 5.5 V
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 | IH2 | | | | | _= | | | | | lccr | l _{CCH} | Same tests, terminal conditions and limits as for subgroup 1, except Tc = 125°C and V_{IC} tests are omittec |
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| | Test no. | method Test no. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 4.5V 5.5V 5.5V 6.5V 16mA 10mA 10mA <t< td=""><td>method Test no. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 4.5 V 5.5 V 4.5 V 5.5 V 16 mA 17<!--</td--><td>method Test no. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 16 mA 1Y 1Y 1Y 3 5.5 V 16 mA 2.0 V 16 mA 2.0 V 16 mA 3Y 3Y 4 1 5.5 V 16 mA 2.0 V 16 mA 2.0 V 16 mA 4Y</td><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 4.5 V 5.5 V 4.5 V 5.5 V 16 mA 1Y 4 1Y 1Y 1Y 1Y 1Y 1Y 1X 1X</td></td></t<> <td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 1 5.5 V 16 mA 1 6.5 V 16 mA 1/Y 1/Y 1/Y 1/Y 3 1 2.0 V 16 mA 1 1 1/Y 1/Y 1/Y 1/Y 4 1 2.0 V 16 mA 1 1 1/Y 4/Y 1/Y 1/Y 1/Y 5 1</td> <td>method Testino. 1A 2V 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 1 5.5V 16 mA " " " 1Y terminal Min 3007 1 2.0V 16 mA " " " 1Y 1Y 4 " 5.5V 16 mA " " " 4Y 4Y 5 " " 5.5V 16 mA " " 4Y 4Y 6 " " " 5.5V 16 mA " 16 mA " 4Y 8 5.5V 4.5V 5.5V 5.5V 16 mA " 16 mA 5.5V 6Y</td> <td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 2.5 V 16 mA 2.0 V 10 mA 2.0 V</td> <td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 1Y terminal Min 3 </td> <td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 1Y 1Y terminal Min 3007 1 2.0 V 16 mA 1 <t< td=""><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 2.0 V 16 mA 1Y 1Y 1Y 3 5.5 V 16 mA 5.5 V 16 mA 1 1 1 1 4 1 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4</td><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 16 mA 5.5V 4.5V 5.5V 16 mA 1Y terminal Min 3007 1 2.0V 16 mA 1<!--</td--><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 1.7 1 mA 1 mA 1.7 1 mA 1.7 1 mA 1 mA 1.7 1 mA 1 mA 1 mA 1 mA 1 mA <td< td=""><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 16 mA 5.5V 16 mA 5.5V 16 mA 1Y 1Y 1Y 3 5.5V 16 mA 2.0V 16 mA 1 1 4 1Y 1Y 1Y 4 1 2.0V 16 mA 1 16 mA 1 4 1 4 1 4 1 4 4 1 4
 4 4</td><td>method Test no. 1A 2Y 2A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 5.5V 16 mA 5.5V 16 mA 1</td><td>method Test no. 1A 2Y 2A Voc. 3A 3Y 4A 4Y 5A 6N 6N 6A 1Y terminal Min 3007 1 2.0V 16 mA 2.0V 16 mA " 5.5V 16 mA 1Y 1 3 " 5.5V 16 mA " 5.5V 16 mA " 16 mA " 1Y 1 5 " 10 N 16 mA " 16 mA " 1Y 1 6 " " 10 N 16 mA " 16 mA " 1Y 1 6 " " 10 N 10 N 16 mA " 10 N 1 1 1 1 10 N 5.5V 1.0 M 5.5V 1.0 M 5.5V 1.1 M 1 1 1 1 1.1 M " 1.2 M 5.5V " 1.2 M 1.1 M 1 1 1</td><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 5.0V 4.5V 5.5V 4.5V 5.5V 16 mA 2.7V 16 mA 1Y 1P 1P 3007 1 6 5.5V 16 mA 2Y 3Y 3Y 5 </td><td>method Testino 1A 2Y 2A Voc 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 50V 45V 45V 55V 46M 55V 16mA 20V 16mA 27V 16mA 27V 16mA 27V 16mA 27V 16mA 27V 47V 16mA 27V 47V 47V</td><td> March Testro. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y Iterminal Min Min</td><td> March Test no. 1</td><td> Method Testino. 14</td><td> Method Test no. 14</td><td> method Test no.</td><td> March Test no. 14 27 24 V_{CC} 34 37 44 47 55 55 V 16 mA 17 18 18 Min 18</td><td> March of Test no.</td><td>method Test no. 14 27 2A V_{CC} 3A 3Y 4A AY 5A GND 6Y 6A 1Y lemminal Min 3007 1 25V 16mA 25V 16mA 2V 16mA 2V 1Y 1Y 4 1 55V 16mA 25V 16mA 2V 1Y 1Y 5 1</td><td> March Test no. 14 27 24 Voc 34 37 44 47 55 55 55 65 65 65 65 6</td><td>method Test no. 1A 2Y 2A Voc. 3A 4A 4Y 5A GND 6Y 6A 1Y terminal Min 300 1 55V 16mA 55V 16mA 55V 16mA 2V 1Y 1PM 2V 2V 1PM 2V 2V 1PM 2V 2V</td><td> March Testino, 144 2Y 2A V_{CC} 3A 3Y 4A 4Y 6A 55 V 6 M 6Y 6A 1Y 6 minal Min 100 1</td><td> March Testino Testin</td><td>4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 5.5V 6ND 6.5SV 16 mA 2.0V 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6.5V 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6ND 6.5SV 6ND 6ND 6ND 6ND 6.5SV 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND</td></td<></td></td></t<></td> | method Test no. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 4.5 V 5.5 V 4.5 V 5.5 V 16 mA 17 </td <td>method Test no. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 16 mA 1Y 1Y 1Y 3 5.5 V 16 mA 2.0 V 16 mA 2.0 V 16 mA 3Y 3Y 4 1 5.5 V 16 mA 2.0 V 16 mA 2.0 V 16 mA 4Y</td> <td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 4.5 V 5.5 V 4.5 V 5.5 V 16 mA 1Y 4 1Y 1Y 1Y 1Y 1Y 1Y 1X 1X</td> | method Test no. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 16 mA 1Y 1Y 1Y 3 5.5 V 16 mA 2.0 V 16 mA 2.0 V 16 mA 3Y 3Y 4 1 5.5 V 16 mA 2.0 V 16 mA 2.0 V 16 mA 4Y | method Testino. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 4.5 V 5.5 V 4.5 V 5.5 V 16 mA 1Y 4 1Y 1Y 1Y 1Y 1Y 1Y 1X 1X | method Testino. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 1 5.5 V 16 mA 1 6.5 V 16 mA 1/Y 1/Y 1/Y 1/Y 3 1 2.0 V 16 mA 1 1 1/Y 1/Y 1/Y 1/Y 4 1 2.0 V 16 mA 1 1 1/Y 4/Y 1/Y 1/Y 1/Y 5 1
1 1 1 1 1 1 1 1 1 1 | method Testino. 1A 2V 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 1 5.5V 16 mA " " " 1Y terminal Min 3007 1 2.0V 16 mA " " " 1Y 1Y 4 " 5.5V 16 mA " " " 4Y 4Y 5 " " 5.5V 16 mA " " 4Y 4Y 6 " " " 5.5V 16 mA " 16 mA " 4Y 8 5.5V 4.5V 5.5V 5.5V 16 mA " 16 mA 5.5V 6Y | method Testino. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 2.5 V 16 mA 2.0 V 10 mA 2.0 V | method Testino. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 1Y terminal Min 3 | method Testino. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 1Y 1Y terminal Min 3007 1 2.0 V 16 mA 1 <t< td=""><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 2.0 V 16 mA 1Y 1Y 1Y 3 5.5 V 16 mA 5.5 V 16 mA 1 1 1 1 4 1 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4</td><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 16 mA 5.5V 4.5V 5.5V 16 mA 1Y terminal Min 3007 1 2.0V 16 mA 1<!--</td--><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 1.7 1 mA 1 mA 1.7 1 mA 1.7 1 mA 1 mA 1.7 1 mA 1 mA 1 mA 1 mA 1 mA <td< td=""><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 16 mA 5.5V 16 mA 5.5V 16 mA 1Y 1Y 1Y 3 5.5V 16 mA 2.0V 16 mA 1 1 4 1Y 1Y 1Y 4 1 2.0V 16 mA 1 16 mA 1 4 1 4 1 4 1 4 4 1 4</td><td>method Test no. 1A 2Y 2A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 5.5V 16 mA 5.5V 16 mA 1</td><td>method Test no. 1A 2Y 2A Voc. 3A 3Y 4A 4Y 5A 6N 6N 6A 1Y terminal Min 3007 1 2.0V 16 mA 2.0V 16 mA " 5.5V 16 mA 1Y 1 3 " 5.5V 16 mA " 5.5V 16 mA " 16 mA " 1Y 1 5 " 10 N 16 mA " 16 mA " 1Y 1 6 " " 10 N 16 mA " 16 mA " 1Y 1 6 " " 10 N 10 N 16 mA " 10 N 1 1 1 1 10 N 5.5V 1.0 M 5.5V 1.0 M 5.5V 1.1 M 1 1 1 1 1.1 M " 1.2 M 5.5V " 1.2 M 1.1 M 1 1 1</td><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 5.0V 4.5V 5.5V 4.5V 5.5V 16 mA 2.7V 16 mA 1Y 1P 1P 3007 1 6 5.5V 16 mA 2Y 3Y 3Y 5 </td><td>method Testino 1A 2Y 2A Voc 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 50V 45V 45V 55V 46M 55V 16mA 20V 16mA 27V 16mA 27V 16mA 27V 16mA 27V 16mA 27V 47V 16mA 27V 47V 47V</td><td> March Testro. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y Iterminal Min Min</td><td> March Test no. 1</td><td> Method
Testino. 14</td><td> Method Test no. 14</td><td> method Test no.</td><td> March Test no. 14 27 24 V_{CC} 34 37 44 47 55 55 V 16 mA 17 18 18 Min 18</td><td> March of Test no.</td><td>method Test no. 14 27 2A V_{CC} 3A 3Y 4A AY 5A GND 6Y 6A 1Y lemminal Min 3007 1 25V 16mA 25V 16mA 2V 16mA 2V 1Y 1Y 4 1 55V 16mA 25V 16mA 2V 1Y 1Y 5 1</td><td> March Test no. 14 27 24 Voc 34 37 44 47 55 55 55 65 65 65 65 6</td><td>method Test no. 1A 2Y 2A Voc. 3A 4A 4Y 5A GND 6Y 6A 1Y terminal Min 300 1 55V 16mA 55V 16mA 55V 16mA 2V 1Y 1PM 2V 2V 1PM 2V 2V 1PM 2V 2V</td><td> March Testino, 144 2Y 2A V_{CC} 3A 3Y 4A 4Y 6A 55 V 6 M 6Y 6A 1Y 6 minal Min 100 1</td><td> March Testino Testin</td><td>4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 5.5V 6ND 6.5SV 16 mA 2.0V 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6.5V 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6ND 6.5SV 6ND 6ND 6ND 6ND 6.5SV 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND</td></td<></td></td></t<> | method Testino. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 2.0 V 16 mA 1Y 1Y 1Y 3 5.5 V 16 mA 5.5 V 16 mA 1 1 1 1 4 1 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4 1 4 | method Testino. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 16 mA 5.5V 4.5V 5.5V 16 mA 1Y terminal Min 3007 1 2.0V 16 mA 1 </td <td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 1.7 1 mA 1 mA 1.7 1 mA 1.7 1 mA 1 mA 1.7 1 mA 1 mA 1 mA 1 mA 1 mA <td< td=""><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 16 mA 5.5V 16 mA 5.5V 16 mA 1Y 1Y 1Y 3 5.5V 16 mA 2.0V 16 mA 1 1 4 1Y 1Y 1Y 4 1 2.0V 16 mA 1 16 mA 1 4 1 4 1 4 1 4 4 1 4</td><td>method Test no. 1A 2Y 2A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 5.5V 16 mA 5.5V 16 mA 1</td><td>method Test no. 1A 2Y 2A Voc. 3A 3Y 4A 4Y 5A 6N 6N 6A 1Y terminal Min 3007 1 2.0V 16 mA 2.0V 16 mA " 5.5V 16 mA 1Y 1 3 " 5.5V 16 mA " 5.5V 16 mA " 16 mA " 1Y 1 5 " 10 N 16 mA " 16 mA " 1Y 1 6 " " 10 N 16 mA " 16 mA " 1Y 1 6 " " 10 N 10 N 16 mA " 10 N 1 1 1 1 10 N 5.5V 1.0 M 5.5V 1.0 M 5.5V 1.1 M 1 1 1 1 1.1 M " 1.2 M 5.5V " 1.2 M 1.1 M 1 1 1</td><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 5.0V 4.5V 5.5V 4.5V 5.5V 16 mA 2.7V 16 mA 1Y 1P 1P 3007 1 6 5.5V 16 mA 2Y 3Y 3Y 5 </td><td>method Testino 1A 2Y 2A Voc 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 50V 45V 45V 55V 46M 55V 16mA 20V 16mA 27V 16mA 27V 16mA 27V 16mA 27V 16mA 27V 47V 16mA 27V 47V 47V</td><td> March Testro. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y Iterminal Min Min</td><td> March Test no. 1</td><td> Method Testino. 14</td><td> Method Test no. 14</td><td> method Test no.</td><td> March Test no. 14 27 24 V_{CC} 34 37 44 47 55 55 V 16 mA 17 18 18 Min 18</td><td> March of Test no.</td><td>method Test no. 14 27 2A V_{CC} 3A 3Y 4A AY 5A GND 6Y 6A 1Y lemminal Min 3007 1 25V 16mA 25V 16mA 2V 16mA 2V 1Y
1Y 4 1 55V 16mA 25V 16mA 2V 1Y 1Y 5 1</td><td> March Test no. 14 27 24 Voc 34 37 44 47 55 55 55 65 65 65 65 6</td><td>method Test no. 1A 2Y 2A Voc. 3A 4A 4Y 5A GND 6Y 6A 1Y terminal Min 300 1 55V 16mA 55V 16mA 55V 16mA 2V 1Y 1PM 2V 2V 1PM 2V 2V 1PM 2V 2V</td><td> March Testino, 144 2Y 2A V_{CC} 3A 3Y 4A 4Y 6A 55 V 6 M 6Y 6A 1Y 6 minal Min 100 1</td><td> March Testino Testin</td><td>4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 5.5V 6ND 6.5SV 16 mA 2.0V 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6.5V 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6ND 6.5SV 6ND 6ND 6ND 6ND 6.5SV 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND</td></td<></td> | method Testino. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A GND 6Y 6A 1Y terminal Min 3007 1 2.0 V 16 mA 5.5 V 4.5 V 5.5 V 16 mA 1.7 1 mA 1 mA 1.7 1 mA 1.7 1 mA 1 mA 1.7 1 mA 1 mA 1 mA 1 mA 1 mA <td< td=""><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 16 mA 5.5V 16 mA 5.5V 16 mA 1Y 1Y 1Y 3 5.5V 16 mA 2.0V 16 mA 1 1 4 1Y 1Y 1Y 4 1 2.0V 16 mA 1 16 mA 1 4 1 4 1 4 1 4 4 1 4</td><td>method Test no. 1A 2Y 2A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 5.5V 16 mA 5.5V 16 mA 1</td><td>method Test no. 1A 2Y 2A Voc. 3A 3Y 4A 4Y 5A 6N 6N 6A 1Y terminal Min 3007 1 2.0V 16 mA 2.0V 16 mA " 5.5V 16 mA 1Y 1 3 " 5.5V 16 mA " 5.5V 16 mA " 16 mA " 1Y 1 5 " 10 N 16 mA " 16 mA " 1Y 1 6 " " 10 N 16 mA " 16 mA " 1Y 1 6 " " 10 N 10 N 16 mA " 10 N 1 1 1 1 10 N 5.5V 1.0 M 5.5V 1.0 M 5.5V 1.1 M 1 1 1 1 1.1 M " 1.2 M 5.5V " 1.2 M 1.1 M 1 1 1</td><td>method Testino. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 5.0V 4.5V 5.5V 4.5V 5.5V 16 mA 2.7V 16 mA 1Y 1P 1P 3007 1 6 5.5V 16 mA 2Y 3Y 3Y 5 </td><td>method Testino 1A 2Y 2A Voc 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 50V 45V 45V 55V 46M 55V 16mA 20V 16mA 27V 16mA 27V 16mA 27V 16mA 27V 16mA 27V 47V 16mA 27V 47V 47V</td><td> March Testro. 1A 2Y 2A V_{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y Iterminal Min Min</td><td> March Test no. 1</td><td> Method Testino. 14</td><td> Method Test no. 14</td><td> method Test no.</td><td> March Test no. 14 27 24 V_{CC} 34 37 44 47 55 55 V 16 mA 17 18 18 Min 18</td><td> March of Test no.</td><td>method Test no. 14 27 2A V_{CC} 3A 3Y 4A AY 5A GND 6Y 6A 1Y lemminal Min 3007 1 25V 16mA 25V 16mA 2V 16mA 2V 1Y 1Y 4 1 55V 16mA 25V 16mA 2V 1Y 1Y 5 1</td><td> March Test no. 14 27 24 Voc 34 37 44 47 55 55 55 65 65 65 65 6</td><td>method Test no. 1A 2Y 2A Voc. 3A 4A 4Y 5A GND 6Y 6A 1Y terminal Min 300 1 55V 16mA 55V 16mA 55V 16mA 2V 1Y 1PM 2V 2V 1PM 2V 2V 1PM 2V 2V</td><td> March Testino, 144 2Y 2A V_{CC} 3A 3Y 4A 4Y 6A 55 V 6 M 6Y 6A 1Y 6 minal Min 100 1</td><td> March Testino Testin</td><td>4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 5.5V 6ND 6.5SV 16 mA 2.0V 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6.5V 6ND 6.5SV 6ND 6.5SV 6ND 6.5SV 6ND 6ND 6.5SV 6ND 6ND 6ND 6ND 6.5SV 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND 6ND</td></td<> | method Testino. 1A 2Y 2A V _{CC} 3A 3Y 4A 4Y 5A 5Y GND 6Y 6A 1Y terminal Min 3007 1 2.0V 16 mA 5.5V 16 mA 5.5V 16 mA 1Y 1Y 1Y 3 5.5V 16 mA 2.0V 16 mA 1 1 4 1Y 1Y 1Y 4 1 2.0V 16 mA 1 16 mA 1 4 1 4 1 4 1 4 4 1 4
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		Limits	Min	3	=	=	=	=	=	3	=	=	=	=	-	3	=	=	=	:	=	က	=	=	=	=		
		Measured	terminal	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	5A to 5Y	6A to 6Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	5A to 5Y	6A to 6Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	5A to 5Y	6A to 6Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	5A to 5Y	6A to 6Y	
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08 - Co 2.0 V, lo		_				-		_						-						_								
ce type high ≥	6	1	2A					Z						Z						Z						Z		
<u>for devi</u> may be	8	80	4Υ				DO						OUT						OUT						OUT			
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up A ins	9	9	37			DO						DOT						OUT						OUT				
III. <u>Gro</u> Is (pins	2	2	3A			Z						z						z						z				
TABLE III. Group A inspection for device type 08 - Continued. conditions (pins not designated may be high ≥ 2.0 V, low ≤ 0.8 V or open)	4	14	Vcc	5.0 V				-		5.0 V					-	5.0 V				:		5.0 V		-				Tc = -55°C.
Terminal	3	က	2A		z						Z						Z						z					
ř	2	4	2Y		TNO						TUO						OUT						OUT					ibgroup 10
	1	-	1A	Z						Z						Z						z						ts as for su
	MIL-STD- Cases A, B, D	Case C	Test no.	39	40	41	42	43	44	45	46	47	48	49	20	51	25	23	24	22	26	57	28	29	09	61	62	Same tests, terminal conditions and limits as for subgroup 10, except
	MIL-STD-	883	method	3003	(Fig. 3)					3003	(Fig. 3))				3003	(Fig. 3)					3003	(Fig. 3))				s, terminal
		Symbol		THd	!				_	t _{PLH}	_	_		_		THd			_	_		t _{PLH}		_				Same test
		Subgroup		6	Tc = 25°C											10	Tc = 125°C											11

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| terminal | 7 ₹ | 37 | ∠ ∠

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 | Vcc | |
| V _{CC} | 4.5 V | | 4.5 V

 | - | | | =
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 | : = | = | | | 2.4 V | GND
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| 2Y | 16 mA | |

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 | | |
| 2B | 5.5 V
2.0 V | 5.5 \ | 5.5 V

 | 4.5 V | 0.8 V | > 2.5 | :
 | = | | | -12mA | - | | | GND
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B | = | 5.5 \ | GN = | | | 5.5 V | =
 | 0.4 V | 5.5 V | | : : | 5.5 V
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2.0 V | 5.5 V | 5.5 V

 | 0.8 V | 4.5 \ | > 5.5 | =
 | = | | -12mA | | | | | GND
"
 | | GND | = | | : : | GND
B | 5.5 V | GND | | | | 5.5 V | 0.4 V
 | 5.5 V | = | | : : | 5.5 V
 | GND | |
| 17 | 16 mA | | 5.5 V

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| 1B | 2.0 V
5.5 V | | 4.5 V

 | 5.5 \ | | | =
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6.5 V 6.5 V 6.5 V 6.5 V 6.5 V 4.5 V 1Y 6 4.5 V 0.8 V 4.5 V 5.5 V 6.5 V 6.5 V 6.5 V 6.5 V 4.5 V 1Y 6 4.5 V 0.8 V 1.7 V <</td><td>method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{CC} terminal Vol. 3007 1 2.0 V 2.0 V 16 MA 5.5 V 16 MA 6.5 V 6.5 V 6.5 V 17 17 Vol. 3007 1 2.0 V 16 MA 2.0 V 16 MA 2.0 V 17 17 Vol. 3 1 1 16 MA 2.0 V 16 MA 2.0 V 17 4 <t< td=""><td>method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{CC} terminal Vol. 3007 1 2.0 V 2.0 V 16 mA 5.5 V 16 mA 5.5 V 17 17 27 17 17 18 18 18 4 4 4 18 V_{CC} 17 17 18 18 18 4 4 18 V_{CC} 17 17 17 18 18 18 4 4 4 18 7 18</td></t<></td></td></td<> <td>welton Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{CC} terminal Vol. 3007 1 2.0 V 2.0 V 16 MA 5.5 V 6.5 V 6.5 V 6.5 V 6.5 V 4.5 V 1Y 2Y 1Y 1Y 2Y 1Y 1Y 1X 1X</td> <td>welloo Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{CC} terminal Vol. 3007 1 2.0 V 2.0 V 16 mA 5.5 V 16 mA 5.5 V 17 17 27 17 17 18 18 4 4 4 4.5 V 17 17 18 18 4.5 V 18</td> <td>Vol. method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{OC} terminal Vol. 3007 1 2.0 V 2.0 V 16 MA 5.5 V 16 MA 5.5 V 17 17 17 17 17 18 18 17 14 17 17 18 18 17 17 18 18 18 17 18 18 18 18 18 17 17 18 18 18 17 18 18 18 18 17 18 18 18 18 18 17 18 1</td> <td> method Test no. 1A</td> <td>wethod Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B Voc terminal Vol. 3007 1 2.0 V 2.0 V 16 mA 5.5 V 16 mA 5.5 V 5.5 V 4.5 V 17 Vol. 3007 1 2.0 V 2.0 V 16 mA 2.0 V 16 mA 2.0 V 17 27 1cx 3 3 3 3 3 4.5 V 5.5 V 5.5 V 16 mA 2.0 V 17 4.5 V 17 1cx 4 4 5 5 4 5.5 V 5.5 V 16 mA 2.0 V 17 4</td> <td> method Test no. 14 18 17 2A 2B 27 GND 37 3A 3B 47 4A 4B V_{GC} teminal V_{OL} 3007 1 2.0 V 2.0 V 16 mA 5.5 V 5</td> <td>Method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{OC} Vo. 307 1 2.0V 2.0V 16 mA 5.5V 6ND 5.5V 5.5V 6ND 5.5V 5.5V 4.5V 1 7 4.5V 1 7 4.5V 1 2 1 4 4 5 4 5 4 5 4 5 4</td> <td> method Test no. 14 18 17 2A 2B 27 GND 37 3A 3B 47 4A 4B Voc terminal Test no. 15 10 Vol. 3007 1 2.0 V 16 mA 2.0 V 16 mA 2.0 V 2.0 V 17 37 37 37 37 37 37 37</td> <td> method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{GC} terminal V_{OL} 3007 1 2.0 V /td> <td> Method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{CC} terminal Method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{CC} 45V 1Y 1Y 1</td> <td> Method Test no. 1A 1B 1V 2A 2B 2V GND 3V 3A 3B 4V 4A 4B V_{OC} terminal Test no. 1A 1B 1V 2A 2B 2V GND 55V 55V 55V 55V 45V 1V 1V 1V 1V 1V 1V 1V </td> <td> Method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{OC} 1Y 1Y 1X 1X 1X 1X 1X 1X</td> <td> Method Test no. 14 18 17 2A 2B 2V GND 3V 3A 3B 4V 4A 4B V_{GC} terminal 17 20V 2.0V 6.6V 6.6</td> <td> Method Testino, 14 18 14 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{CC} terminal 1 1 2.00 1</td> <td> Mothed Test from 1A 18 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V_{GC} 1 1 1 1 1 1 1 1 1 </td> <td> Modelloon Tost Incomposed Modelloon Mode</td> <td> Marcheol Test no. 1</td> <td> More Test</td> <td> Maried Test no. 14 15</td> <td> Morino Testron 154 156 174 254 256</td> 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V 2.0 V 17 37 37 37 37 37 37 37 | method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V _{GC} terminal V _{OL} 3007 1 2.0 V 2.0 V | Method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V _{CC} terminal Method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V _{CC} 45V 1Y 1Y 1 | Method Test no. 1A 1B 1V 2A 2B 2V GND 3V 3A 3B 4V 4A 4B V _{OC} terminal Test no. 1A 1B 1V 2A 2B 2V GND 55V 55V 55V 55V 45V 1V 1V 1V 1V 1V 1V 1V | Method Test no. 1A 1B 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V _{OC} 1Y 1Y 1X 1X 1X 1X 1X 1X | Method Test no. 14 18 17 2A 2B 2V GND 3V 3A 3B 4V 4A 4B V _{GC} terminal 17 20V 2.0V 6.6V 6.6 | Method Testino, 14 18 14 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V _{CC} terminal 1 1 2.00 1 | Mothed Test from 1A 18 1Y 2A 2B 2Y GND 3Y 3A 3B 4Y 4A 4B V _{GC} 1 1 1 1 1 1 1 1 1 | Modelloon Tost Incomposed Modelloon Mode | Marcheol Test no. 1 | More Test | Maried Test no. 14 15 | Morino Testron 154 156 174 254 256 | Mode Test no Test no | Month of Test No. Test No. | Marcol Testino Testi | Marcol Testino Testi | The color Total from Tota | Marcial Testino Test | Marchaed Testino 144 149 147 224 228 224 0340 347 348 448 |

			ts	Мах	23	=	=		28	=	=		59	=	=		35	=	=		
			Limits	Min	3	=			3	=			3	=	=		က	=			
			Measured	terminal	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	1A to 1Y	2A to 2Y	3A to 3Y	4A to 4Y	
		14		Vcc	5.0 V	=			5.0 V				5.0 V	=			5.0 V			"	
		13		4B				2.4 V				2.4 V				2.4 V				2.4 V	
	open)	12		4A				Z				Z				Z				Z	
.per	0.8 V or	11		47				TUO				DOUT				DOUT				OUT	
- Continu	V , $low \le$	10		3B			2.4 \				2.4 \				2.4 \				2.4 \		
TABLE III. Group A inspection for device type 09 - Continued.	erminal conditions (pins not designated may be high ≥ 2.0 V, low ≤ 0.8 V or open)	6		3A			Z				Z				Z				Z		
or device	ay be hiç	8		37			OUT				OUT				DOUT				OUT		
ection fo	Inated m	7		GND	GND				GND				GND				GND				
dsui A dr	not desig	9		2Y		TUO				TUO				DOT				DOUT			
Grou	ıs (pins ı	2		2B		2.4 \				2.4 V				2.4 \				2.4 V			
TABLE	condition	4		2A		z				Z				Z				Z			except Tc = -55°C.
	Terminal	3		1	TUO				TUO				TUO				OUT				0, except T
		2		18	2.4 V				2.4 V				2.4 V				2.4 V				subgroup 1
		1		1A	Z				Z				Z				Z				imits as for
		Case C		Test no.	47	48	49	20	51	52	53	24	22	26	22	28	29	09	61	62	Same tests, terminal conditions and limits as for subgroup 10,
		MIL-STD-	883	method	3003	(Fig. 3)			3003	(Fig. 3))		3003	(Fig. 3)			3003	(Fig. 3)			s, terminal c
			Symbol		tpHL				t _{PLH}				t _{PHL}				t _{PLH}				Same test
			Subgroup Symbol		6	Tc = 25°C							10	Tc = 125°C							11

S = =

S = =

5. PACKAGING

5.1 Packaging requirements. For acquisition purposes, the packaging requirements shall be as specified in the contract or order (see 6.2). When actual packaging of materiel is to be performed by DoD or in-house contractor personnel, these personnel need to contact the responsible packaging activity to ascertain packaging requirements. Packaging requirements are maintained by the Inventory Control Point's packaging activity within the Military Service or Defense Agency, or within the military service's system command. Packaging data retrieval is available from the managing Military Department's or Defense Agency's automated packaging files, CD-ROM products, or by contacting the responsible packaging activity.

6. NOTES

(This section contains information of a general or explanatory nature that may be helpful, but is not mandatory.)

- 6.1 <u>Intended use.</u> Microcircuits conforming to this specification are intended for original equipment design applications and logistic support of existing equipment.
 - 6.2 Acquisition requirements. Acquisition documents should specify the following:
 - a. Title, number, and date of the specification.
 - b. PIN and compliance identifier, if applicable (see 1.2).
 - c. Requirements for delivery of one copy of the conformance inspection data pertinent to the device inspection lot to be supplied with each shipment by the device manufacturer, if applicable.
 - d. Requirements for certificate of compliance, if applicable.
 - e. Requirements for notification of change of product or process to contracting activity in addition to notification to the qualifying activity, if applicable.
 - Requirements for failure analysis (including required test condition of method 5003 of MIL-STD-883), corrective action, and reporting of results, if applicable.
 - g. Requirements for product assurance options.
 - h. Requirements for special carriers, lead lengths, or lead forming, if applicable. These requirements should not affect the part number. Unless otherwise specified, these requirements will not apply to direct purchase by or direct shipment to the Government.
 - i. Requirements for "JAN" marking.
 - J. Packaging requirements (see 5.1).
- 6.3 Superseding information. The requirements of MIL-M-38510 have been superseded to take advantage of the available Qualified Manufacturer Listing (QML) system provided by MIL-PRF-38535. Previous references to MIL-M-38510 in this document have been replaced by appropriate references to MIL-PRF-38535. All technical requirements now consist of this specification and MIL-PRF-38535. The MIL-M-38510 specification sheet number and PIN have been retained to avoid adversely impacting existing government logistics systems and contractor's parts lists.
- 6.4 Qualification. With respect to products requiring qualification, awards will be made only for products which are, at the time of award of contract, qualified for inclusion in Qualified Manufacturers List QML-38535 whether or not such products have actually been so listed by that date. The attention of the contractors is called to these requirements, and manufacturers are urged to arrange to have the products that they propose to offer to the Federal Government tested for qualification in order that they may be eligible to be awarded contracts or purchase orders for the products covered by this specification. Information pertaining to qualification of products may be obtained from DSCC-VQ, P.O. Box 3990, Columbus, Ohio 43218-3990.

6.5 <u>Abbreviations, symbols, and definitions.</u> The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535, MIL-HDBK-1331, and as follows:

GND	Ground zero voltage potential
$V_{IN}\ \dots \dots$	Voltage level at an input terminal
V_{IC}	Input clamp voltage
I _{IN}	Current flowing into an input terminal

- 6.6 <u>Logistic support.</u> Lead materials and finishes (see 3.3) are interchangeable. Unless otherwise specified, microcircuits acquired for Government logistic support will be acquired to device class B (see 1.2.2), lead material and finish A (see 3.3). Longer length leads and lead forming should not affect the part number.
- 6.7 <u>Substitutability.</u> The cross-reference information below is presented for the convenience of users. Microcircuits covered by this specification will functionally replace the listed generic-industry type. Generic-industry microcircuit types may not have equivalent operational performance characteristics across military temperature ranges or reliability factors equivalent to MIL-M-35810 device types and may have slight physical variations in relation to case size. The presence of this information should not be deemed as permitting substitution of generic-industry types for MIL-M-38510 types or as a waiver of any of the provisions of MIL-PRF-38535.

Military device type	Generic-industry type
01	5430
02	5420
03	5410
04	5400
05	5404
06	5412
07	5401
08	5405
09	5403

6.8 <u>Changes from previous issue.</u> Marginal notations are not used in this revision to identify changes with respect to the previous issue due to the extensiveness of the changes.

Custodians:

Army - CR

Navy - EC

Air Force - 11

DLA - CC

Preparing activity: DLA - CC

(Project 5962-2072)

Review activities:

Army - MI, SM

Navy - AS, CG, MC, SH, TD

Air Force - 03, 19, 99

NOTE: The activities listed above were interested in this document as of the date of this document. Since organizations and responsibilities can change, you should verify the currency of the information above using the ASSIST Online database at http://assist.daps.dla.mil.